Application/Control No. Applicant(s)/Patent Under Reexamination 10/613,497 CHEN, TIENTEH Notice of References Cited Examiner Art Unit Page 1 of 1 1774 Betelhem Shewareged **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-5,863,648 01-1999 Ohmura et al. 428/32.37 Α US-2004/0066439 В 04-2004 Kasperchik et al. 347/101 C US-US-D US-Ε US-F US-G US-Н US-1 US-J US-Κ US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W Х

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